## X-ray Absorption Spectroscopy

A short course

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# **Course Objective**

To familiarize students/researchers with the principles, practices and applications of XAFS techniques for materials analysis.

#### **References:**

- J. Stöhr, NEXAFS Spectroscopy (Springer, 1992)
- D. Koningsberger & R. Prins, (eds), X-ray Absorption

Spectroscopy: Principles, Applications and Techniques of

EXAFS, SEXAFS and XANES (Wiley, 1988)

**T.K. Sham** (ed) Chemical Applications of Synchrotron Radiation (World Scientific, 2002)

Frank de Groot and Akio Kotani, Core Level Spectroscopy of Solids (Taylor & Francis CRC press, 2008)

# Relevant questions to be addressed

- What is XAS and XAFS?
- What is synchrotron radiation?
- How to make XAFS measurements?
- How to analyze XAFS Data?
- What information can XAFS provide?

### **Course outline**

- Introduction: materials and the interaction of light with materials
- XAFS spectroscopy the near edge
- XAFS spectroscopy the extended region (EXAFS)

# What is X-ray absorption spectroscopy (XAS)?

- X-ray interacts with all electrons in matter when its energy exceeds the binding energy of the electron.
- X-ray excites or ionizes the electron to a previously unoccupied electronic state (bound, quasi bound or continuum). The study of this process is **XAS**
- Since the binding energy of core electrons is **element specific**, XAS is element and core level specific (e.g. Si K-edge at 1840 eV is the 1s electronic excitation threshold of silicon)

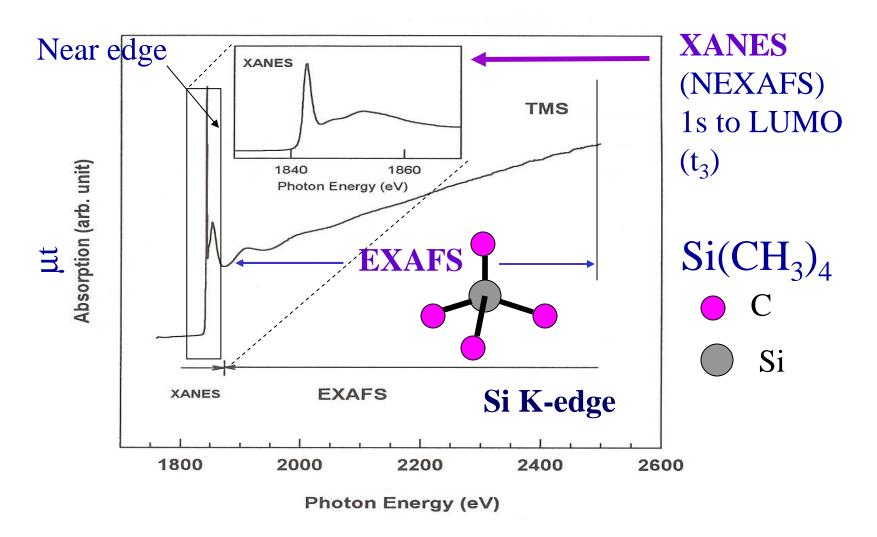
# What is X-ray absorption fine structures (XAFS)?

As core electron is excited with  $hv \ge$  the threshold  $(E_o)$ , it is excited to a final state defined by the **chemical environment**, which modulates the absorption coefficient relative to that of a free atom. This **modulation** is known the **XAFS**,

- XAFS contains all the information about the local structure and bonding of the absorbing atom
- XAFS study requires a **tunable X-ray source** synchrotron radiation

Note: **XAS** and **XAFS** are often used interchangeably, XAS is a general term, XAFS is specific to the modulation of the absorption coefficient by the chemical environment

### What does XAFS look like?

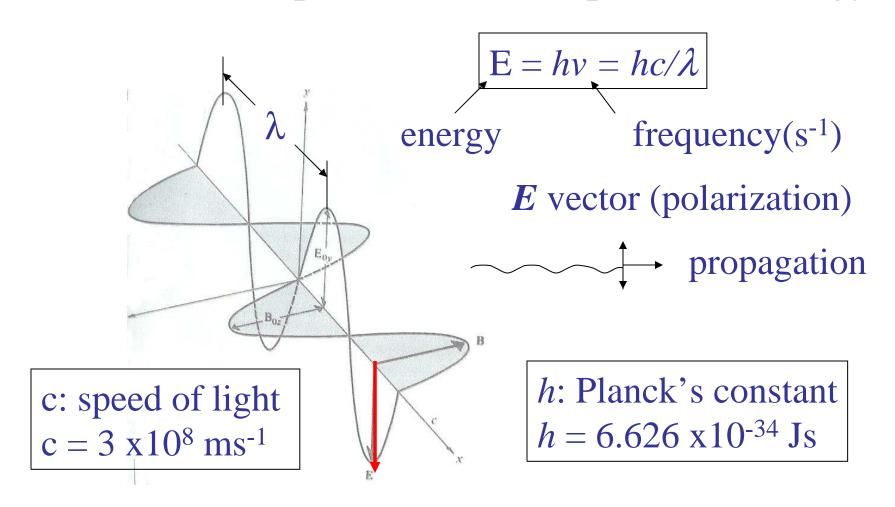


### Part I

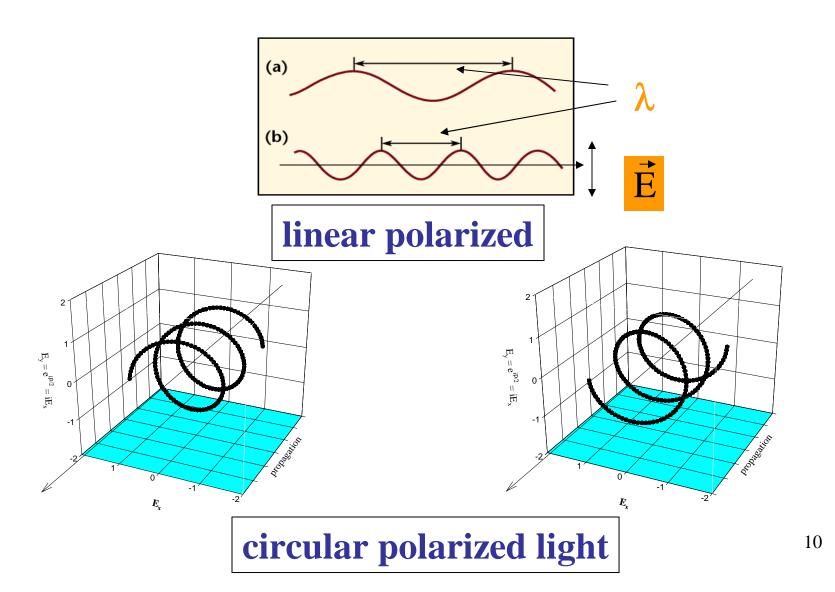
- Light
- Materials
- Synchrotron radiation
- Interaction of light with matter

### Probing matter with SR, versatile *light*

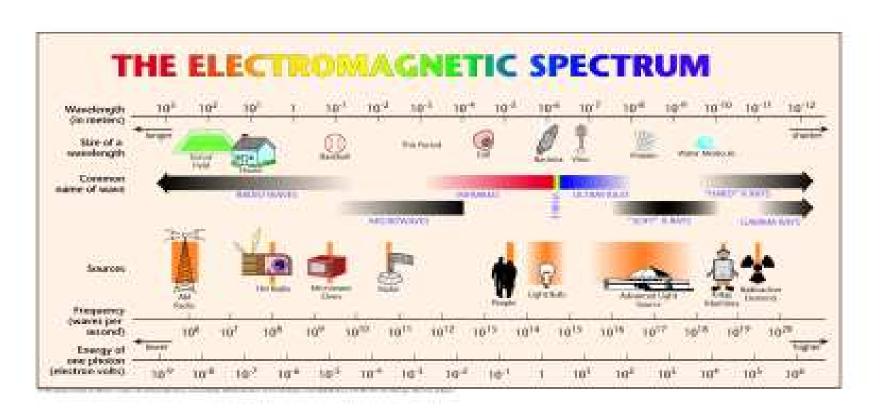
What is *light*? (particle carries a packet of energy)



# Light is a particle (photon) with spin = 1 and behaves like a wave

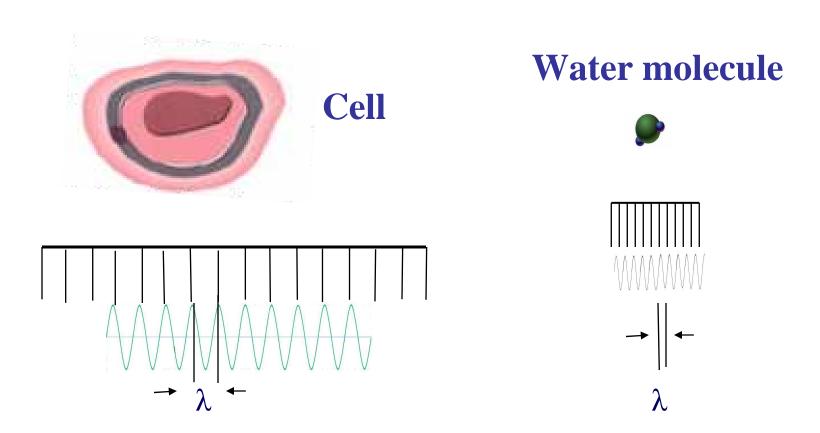


# Electromagnetic wave spectrum $\lambda(\text{Å}) = 12398.5/\text{E}(\text{eV})$



Light sees object with dimension comparable to its wavelength

#### "Rulers" for small sizes: Photons and Electrons



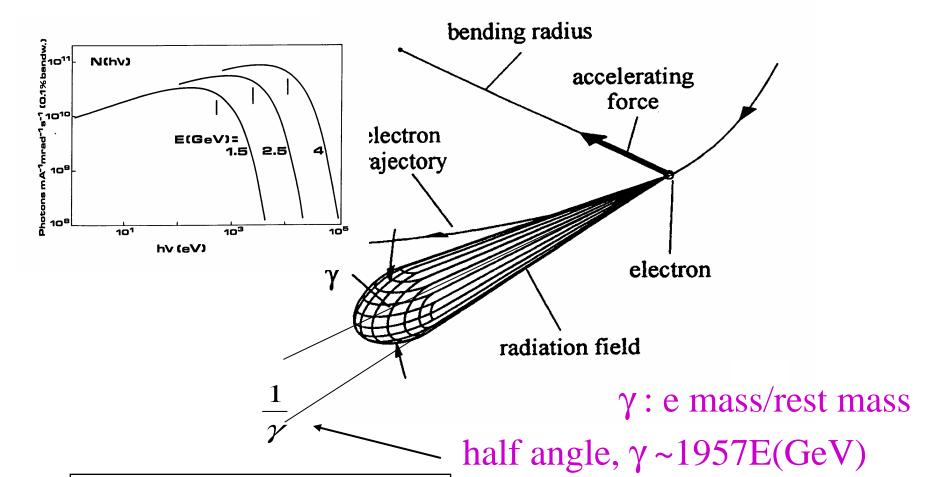
Synchrotron radiation: photons with tunable wavelength,  $\lambda$  (10<sup>4</sup> nm – 10<sup>-3</sup> nm)

# What is synchrotron radiation?

• When an electron traveling at nearly the speed of light in an orbit, it emits a continuum of electromagnetic radiation tangential to the orbit.

Synchrotron light

# Radiation Pattern: Spatial distribution

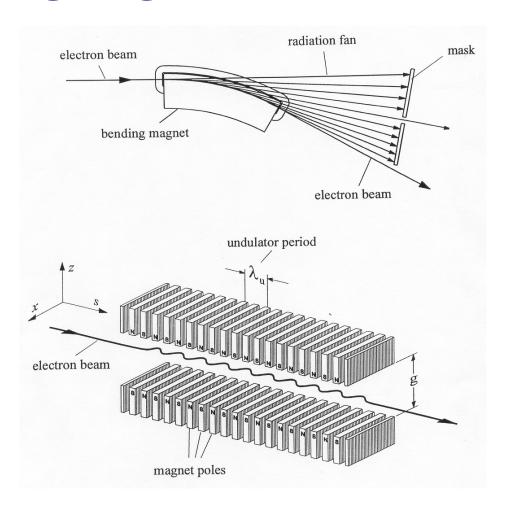


At APS, E = 7.0 GeV

 $1/\gamma = 0.073 \text{ mrad} = 0.0041^{\circ}$ 

→ highly collimated source

## **Bending Magnet and Insertion Device**



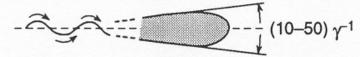
Third generation sources, e.g. APS, ALS, CLS etc are insertion device based sources

# **Spatial distribution**

# **Spectral distribution**



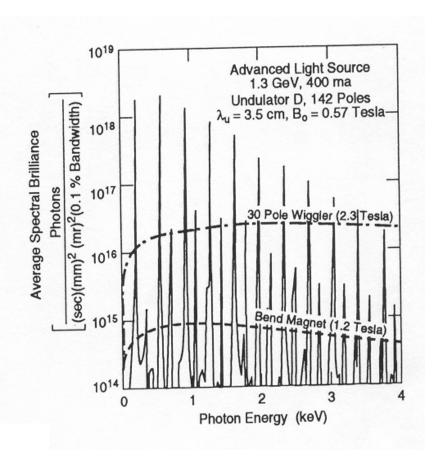
Bending Magnet — A "Sweeping Searchlight"



Wiggler — Incoherent Superposition

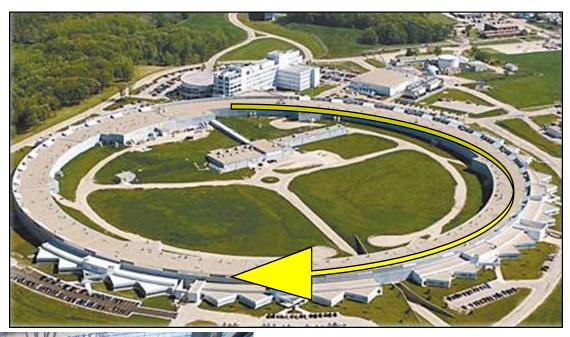


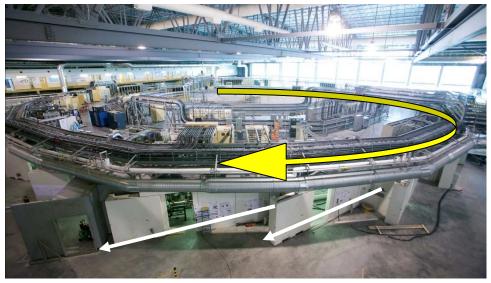
Undulator — Coherent Interference



## **Third Generation Light Sources**

The 7.0 GeV
Advanced
Photon Source
(APS)





The 2.9 GeV
Canadian
Light Source
(CLS)

# Synchrotron radiation properties

- Tunability (IR to hard x-rays, element specific)
- Brightness (highly collimated, micro/nano beam)
- Polarization (linear, circular, tunable, dichroism)
- Time structure (short pulse, dynamics)
- Coherence (undulator, partial; FEL, ~ full, imaging)

#### Materials: matter with desired functionalities

#### General considerations

- Materials can be classified by
- a) phase: gas, liquid and solid
- b) properties: metal, semiconductor, insulator, etc.
- c) composition: pure substance, composite
- d) functionalities: biomaterials, nanomaterials, LED materials, superconductor, soft matter etc.
- Issues in materials analysis
- a) morphology
- b) structure
- c) bonding (electronic structure)

# **Materials Properties**

- Material properties are determined by the electronic structure of the material
- The electronic structure is determined by the behavior of the electron in its environment, technically the *potential* set up by the nuclei and other electrons (structure and bonding) as well as the boundary conditions
- Surface/Interface and proximity effects

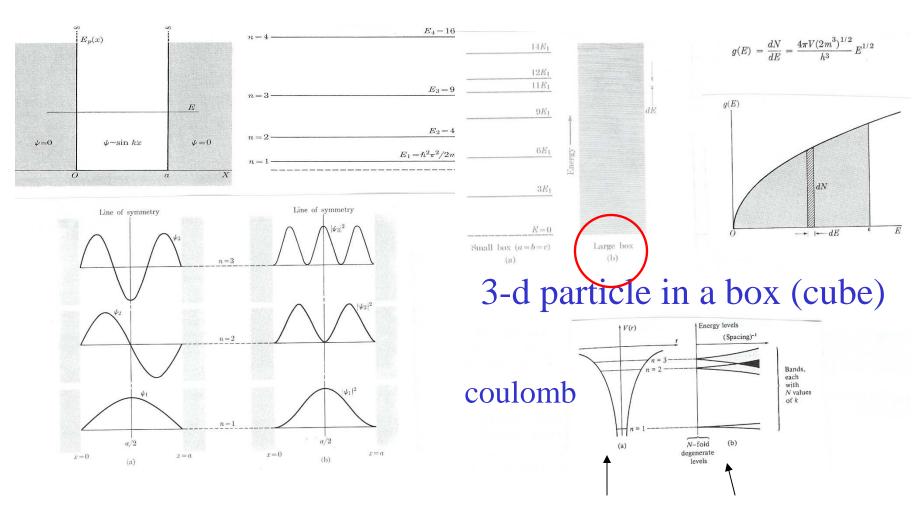
# **Properties of electrons**

- Smallest charge particle that carries a negative charge
- Exhibits wave behavior  $\lambda = h/p$  (de Broglie)
- Posses a spin of ½ (fermions, exchange interaction)
- Absorbs light when it is bound by a *potential* (Free electron does not absorb light)

# Potentials (electrostatic)

- Particle in a box
- Atom: coulomb (asymptote) plus centrifugal (non zero angular momentum, potential barrier)
- Molecule: molecular potential (all nuclei, all electrons)
- Solid: periodic potential (crystals)
- Potential supports discrete energy states (core/valence levels in atoms and molecules) and closely spaced states (bands in solids, polymers, nanostructures)
- Synchrotron spectroscopy studies transitions between occupied and unoccupied states, these transitions are strongly influenced by the local environment, therefore XAFS probes the local environment.

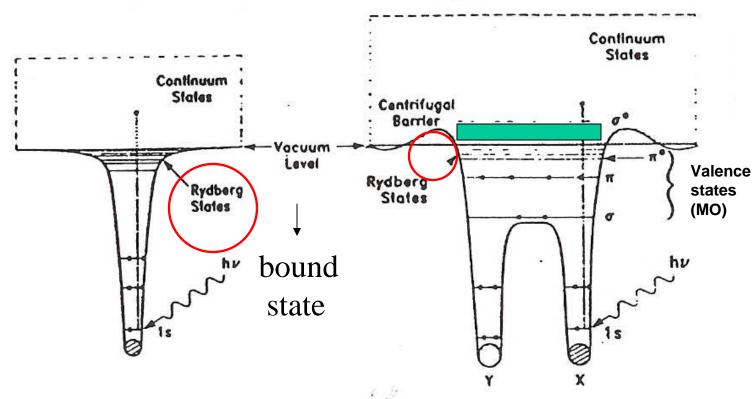
### Potentials and electronic states



1-d particle in a box electronic states are quantized

Single atom N atoms (solid)

### Potential in diatomic molecule



free atom

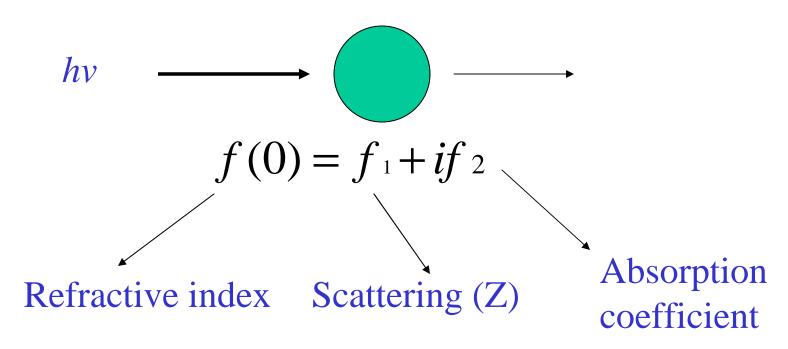
unsaturared diatomic molecule (e.g. double bonds, C=O, O=O, etc.)

# Interaction of light with matter

- Scattering (elastic and inelastic)
- **Absorption** (annihilation of the photon)
- Scattering and absorption are taking place simultaneously
- Magnitude of interaction, scattering amplitude /absorption cross-sections (coefficient) depends on whether or not the photon energy is close to the absorption threshold

### **Atomic scattering factors**

• The interaction of light and atom for photons in the energy range of VUV to soft and hard x-rays (> 30 eV) can be expressed in terms of their scattering factor in the forward scattering position ( $\theta = 0$ )



# How does light interact with matter?

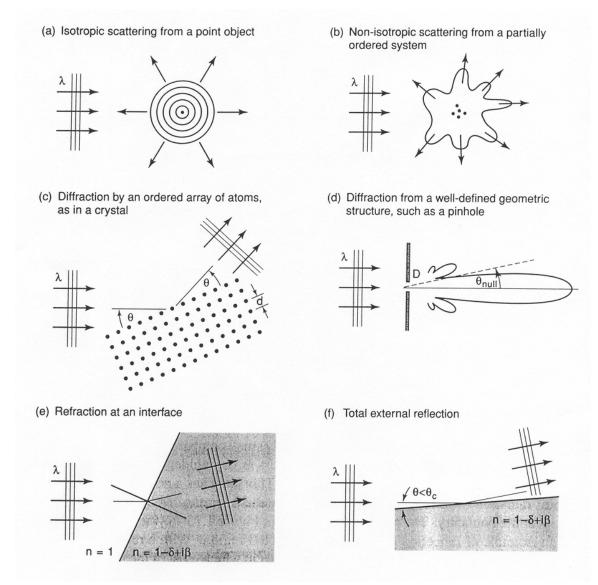
- Scattering (momentum/energy transfer) elastic scattering inelastic
- **Absorption** (annihilation of the photon)

photoabsorption XAFS
photoemission XPS, Augerfluorescence XES
luminescence XEOL

De-excitation spectroscopy

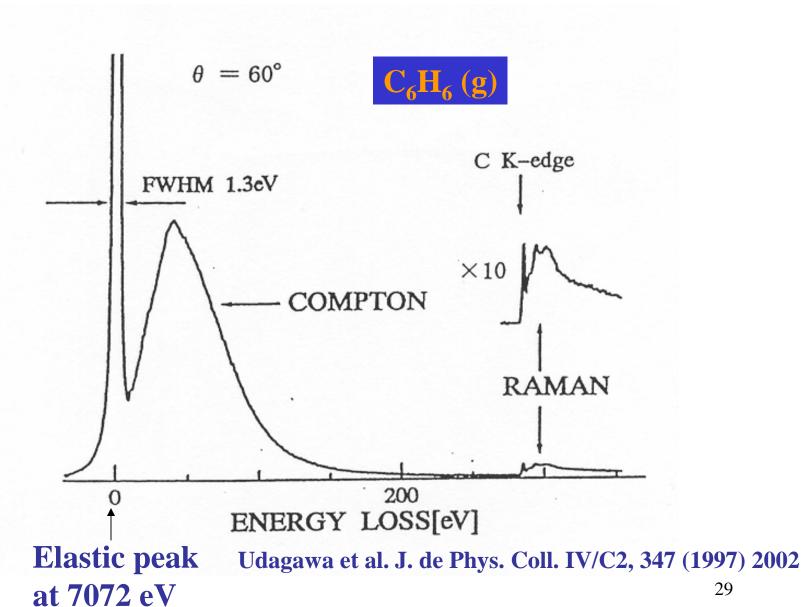
• Resonance (e.g resonant X-ray scattering/emission)

# Some examples of scattering



"Soft X-Rays and Extreme Ultraviolet Radiation: Principles and Applications" D. Atwood Cambridge University press (1999)

### **Inelastic X-ray scattering**



# The overall picture

Absorption and scattering occur simultaneously

• Above and in the vicinity of an *absorption edge* absorption dominates

• Far away from an absorption edge scattering is more important

# X-ray properties of elements

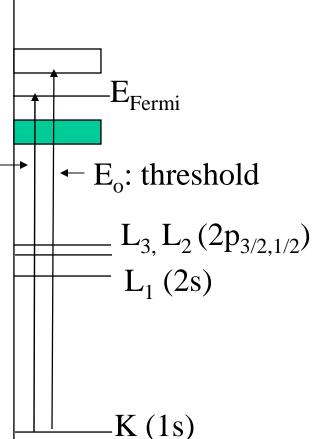
### Electron Binding Energies (eV)

- L<sub>3</sub>: 99.8
- L<sub>2</sub>: 100.4
- $L_1$ : 149.7
- K: 1838.9 BE: binding energy

### Electron Level Widths (eV)

- $L_3$ : 0.014
- $\mathbf{L_2}$ : 0.015  $\Delta \mathbf{E} \cdot \Delta \mathbf{t} \leq \hbar/2\pi$
- $L_1$ : 1.030 Lifetime of the core hole
- K: 0.480

### Silicon (Si) Z = 14



### The refractive index Cu K-edge

$$\begin{split} n &= 1 - \delta + i\beta \\ &= 1 \text{-} (n_a r_e \lambda^2 / 2\pi) \ (f_1^{\ 0} \text{-} i f_2^{\ 0}) \end{split}$$

 $\delta$ : related to scattering  $(f_1^{\ 0})^-$ 

 $\beta$ : related to absorption ( $f_2^0$ )

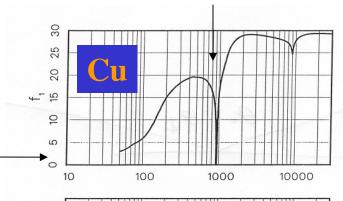
linear absorption coefficient

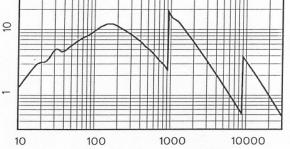
$$\mu = \sigma \cdot \rho \text{ (cm}^{-1})$$

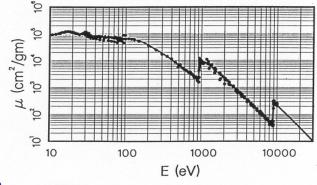
 $\sigma$  = mass absorption (cm<sup>2</sup>/gm) $\rightarrow$ 

 $\rho = \text{density (gm-cm}^{-3})$ 

Henke et al. Atomic Data, Nucl. Data, 54, 181(1993)



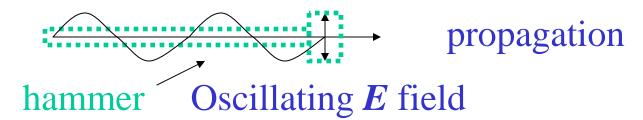




# The absorption process $\rightarrow$ spectroscopy

Photoabsorption is a transition process between quantum states. It excites a core/valence electron into a previously unoccupied *bound states*, *quasi bound states* (excitation) or into the *continuum* (ionization, photoelectric effect).

A photon can be regarded as an **oscillating hammer** of which the oscillating electric field acts as a perturbation to the system (*the hammer knocks the electron out of the core orbital*)



# Transition probability, partial and total absorption cross sections

- Transition probability from a core level (partial absorption cross section) depends on the energy and symmetry of the initial and final states and the photon energy. Spectroscopy implication  $\rightarrow$  *intensity*
- At a given photon energy, all electrons in an atom with threshold energy less than the photon energy can be excited; the **total absorption cross section** is the **sum of all the partial absorption cross sections** of all levels involved

a particular core level (1s, 2s etc.)

The *partial absorption cross-section* (transition probability)  $\sigma$ , can be expressed as

 $\sigma \propto |\langle i|\epsilon \cdot r|f\rangle|^2 \rho(E_f)$ 

Time-dependent perturbation

|i|>: the initial state wave-function, e.g. $\psi_{1s}$ 

ε: electric vector of the synchrotron

**r**: the electric dipole vector

|f|\rightarrow : the final state wave-function,

 $\rho(E_f)$ : the densities of states (occupancy:

bands, unoccupied molecular orbitals and

continuum states).

This expression is known as the Fermi's golden rule.

continuum

**Dipole selection rules** are requirements of the angular momentum characteristic of the initial and final state for allowed transitions

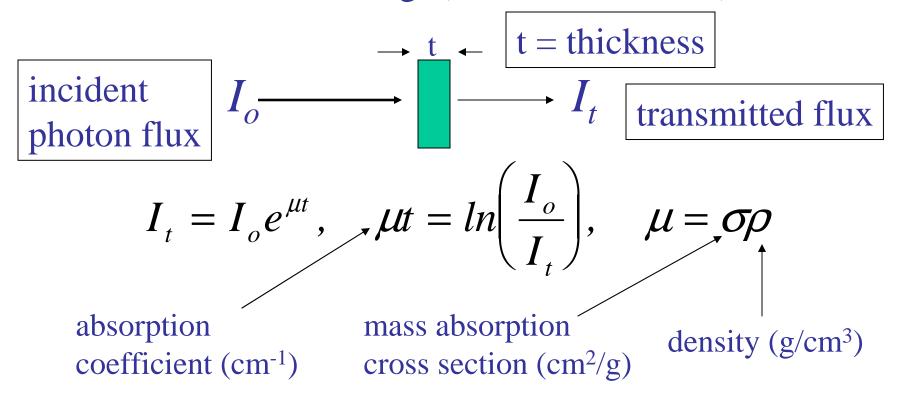
$$\Delta l = \pm 1, \, \Delta j = \pm 1, \, 0.$$

Thus, K (1s) and  $L_1$  (2s) shell ( $\ell = 0$ ) absorption probes final states of p character and

 $L_{3,2}$  shell  $(2p_{3/2,1/2})$  ( $\ell = 1$ ,  $s = \frac{1}{2}$ ,  $j = \frac{3}{2}, \frac{1}{2}$ ) probes final states with d and s character, in general p to d transition is a dominant process

## Mass absorption coefficient

Mass absorption cross section is often expressed in barn/atom or  $cm^2/g$ ; (1 barn =  $10^{-24}$  cm<sup>2</sup>)



**Note**:  $\mu$  or  $\sigma$  is a function of photon energy

## Useful parameters

**Transmission**: % of incident photons transmitted for a given thickness of a uniform sample:

**E.g.** the transmission of 1000 eV photon through a 1 micron (10<sup>-4</sup> cm) graphite film(normal incidence) is

transmission = 
$$\frac{I_t}{I_o}$$
 =  $e^{-\mu t}$  =  $e^{-0.363}$  = 0.886 = 69.6%  
 $\mu = \sigma \rho = (2.298 \times 10^3 cm^2 / g) \times (1.58g / cm^3)$   
=  $3.6308 \times 10^3 cm^{-1}$  mass abs. coeff. density of graphite  
 $\mu t = 3.6308 \times 10^3 cm^{-1} \times 10^{-4} cm = 0.368$ 

## Useful parameters

One-absorption length (hv): the thickness of the sample  $t_1$ , such that  $\mu t = 1$  or  $t_1 = 1/\mu$ 

E.g. the one absorption length of graphite at 1000 eV is

$$\mu = \sigma \rho = 3.36 \times 10^{3} cm^{-1}$$
  
 $t_1 = 1/\mu = 1/3.63 \times 10^{3} cm^{-1} = 2.98 \mu m$ 

$$\frac{I_t}{I_o} = e^{-\mu t} = e^{-1} = 0.368$$

One absorption length corresponds to 37% transmission, 63% absorption

## One absorption length

This is also known as the 1/e attenuation length or simply **attenuation length** by which the incident photon flux has been attenuated to 1/e = 0.368 or 36.8% of its intensity.

One absorption length is often used as an optimum length for the thickness of the sample in XAFS measurement for best signal to noise ratio

## Representative absorption coefficients and one-absorption lengths.

Element Density Energy Mass abs. Coeff. One-abs. length

|                 | (g/cm <sup>3</sup> | (eV)            | $(cm^2/g)$         | (µm)  |
|-----------------|--------------------|-----------------|--------------------|-------|
| Si              | 2.33               | 1840 (K)        | $3.32 \times 10^3$ | 1.3   |
|                 |                    | $100 (L_{3,2})$ | $8.6 \times 10^4$  | 0.05  |
|                 |                    | 30 (VB)         | $1.4 \times 10^4$  | 0.28  |
| C(graphite)1.58 |                    | 300 (K)         | $4.01 \times 10^4$ | 0.16  |
|                 |                    | 30 (VB)         | $1.87 \times 10^5$ | 0.034 |
| Au              |                    | $12000 (L_3)$   | $1.796X10^2$       | 2.88  |

This provides info. about sampling depth

## X-ray absorption is ideal for materials analysis, here is why

- Each element has its set of absorption edges (energy) and decay channels characteristic of the element
- Excitation channel specific (multi dimensional info) dipole selection rules, symmetry
- Sensitive to chemical environment (molecular potential)
- Tunability, high brightness, microbeam, polarization, time structure etc. provide many unprecedented capabilities for materials analysis

## The absorption characteristics and the periodic table of the elements

low z elements: all levels are accessible with VUV (vacuum UV, 30 – 1000 eV) and soft X-rays (1000 – 5000 eV). In this region, absorption is the dominant process (measurement in high vacuum environment)

high z elements: deeper core levels are only accessible with hard X-rays (5000 eV to 40 keV). (measurements can be made in the ambient atmosphere)

Sources of information will be discussed below

The X-ray data booklet are provided in handouts

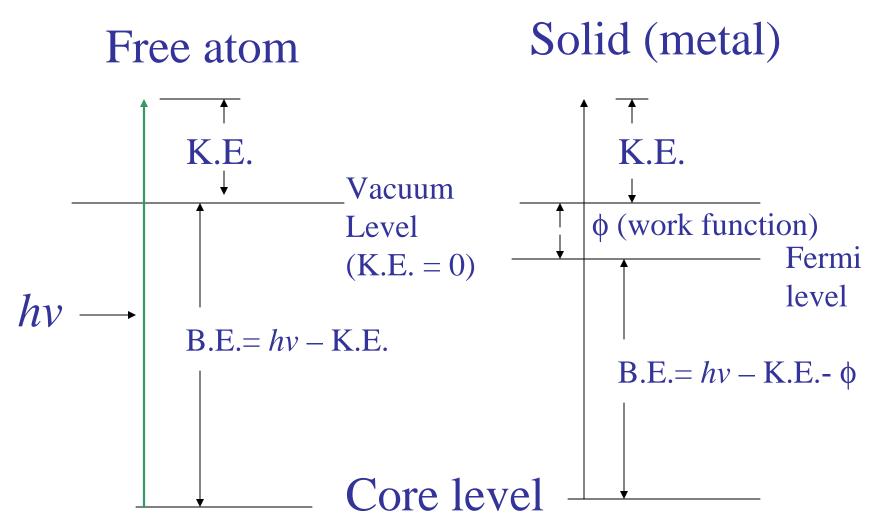
## X-ray Reference Data

- X-ray data booklet (http://xdb.lbl.gov/)
- X-ray calculator (<a href="http://www-cxro.lbl.gov/">http://www-cxro.lbl.gov/</a>)
- Mass absorption table (McMaster et al, 1969) (web: search for UCRL-50174)
- Photoionization cross section table (Yeh and Lindu)
- Radiative and radiationless yield table (Krause)

## selected data from the X-ray booklet

- 1.1 Electron Binding Energy
- 1.2 X-ray Emission Energy
- 1.3 Fluorescence Yield for K and L Shells
- 1.4 Principal Auger Electron Energies
- 1.5 Subshell Photoionization Cross Sections
- 1.6 Mass Absorption Coefficients
- 1.7 Atomic Scattering Factor

## X-ray Binding Energy Table



Theory: RHF one electron energy,  $\varepsilon_i$  , i, core level of interest

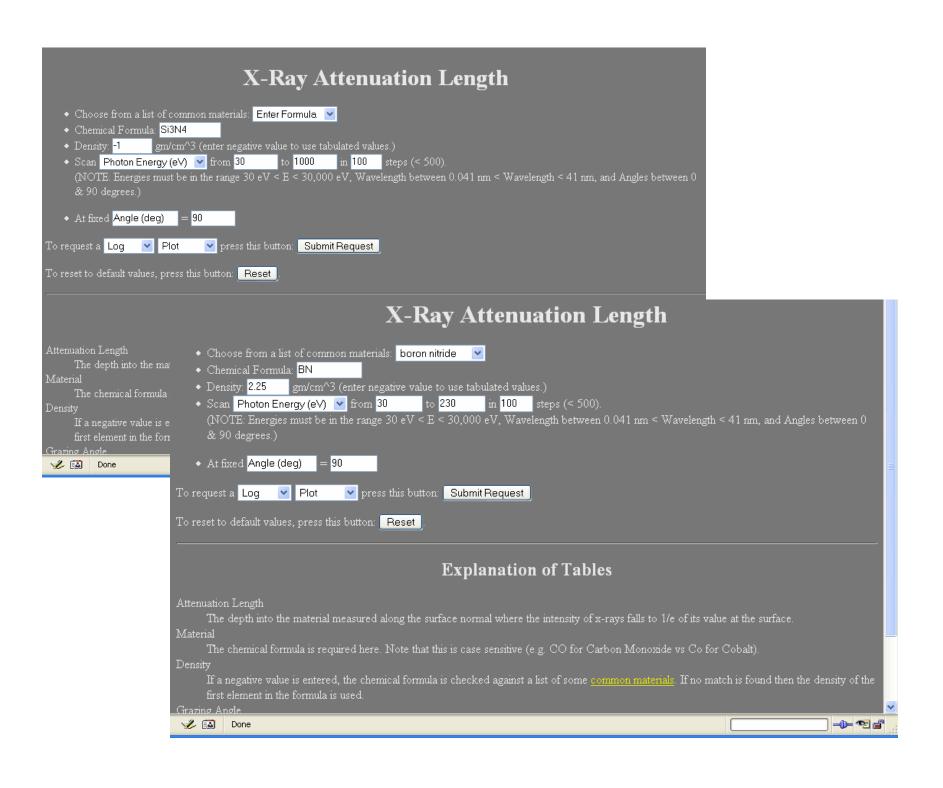
# Calculation of X-ray absorption coefficient

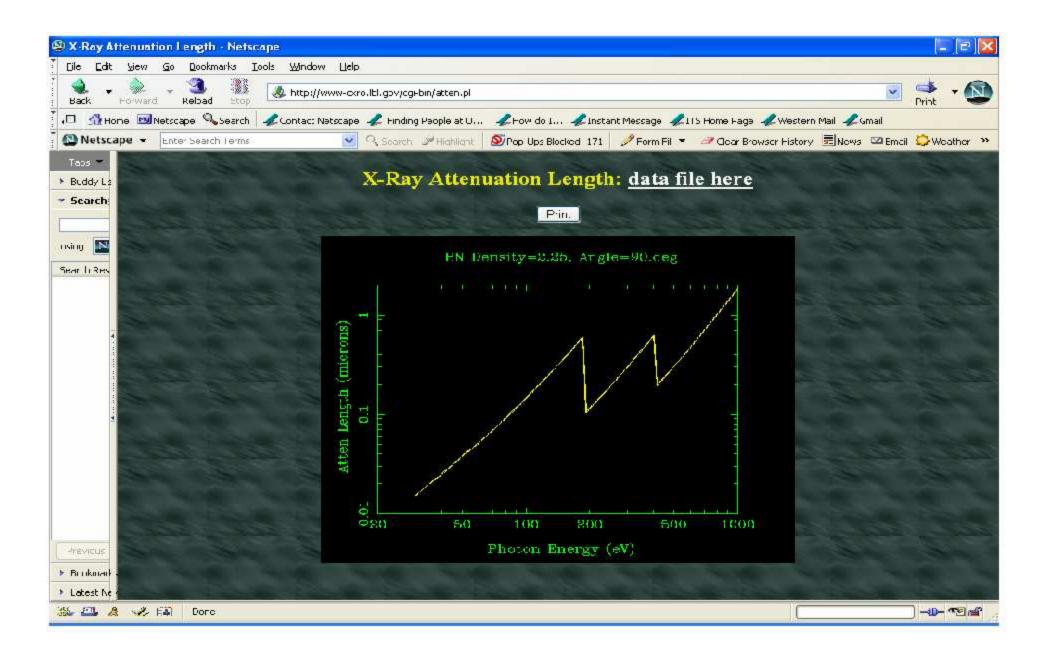
The following web site
 http://henke.lbl.gov/optical\_constants/
 can be used to calculate absorption and
 related parameters based on atomic cross sections (free atom! without the modulation
 by the chemical environment)

## The X-ray calculator

- 1. Go to the web: <a href="http://www-cxro.lbl.gov/">http://www-cxro.lbl.gov/</a>
- 2. Click "x-ray tools" on the left panel
- 3. Click on "x-ray interaction with matter calculator" you will find the content of information from which x-ray properties of elements, attenuation length, transmission of gas and solid are most relevant to x-ray spectroscopy.

**Exercise:** Use the calculator to calculate the x-ray properties of the materials relevant to your research

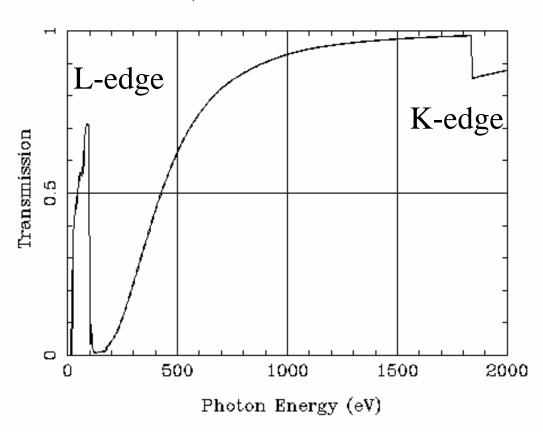




## **Example: Si**

#### **Filter Transmission**

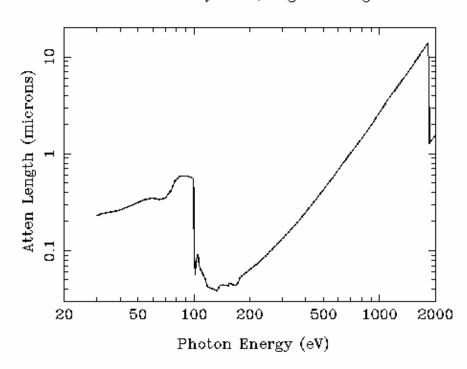
Si Density=2.33 Thickness=0.2 microns



### The attenuation length of Si

#### X-Ray Attenuation Length

Si Density=2.33, Angle=90.deg



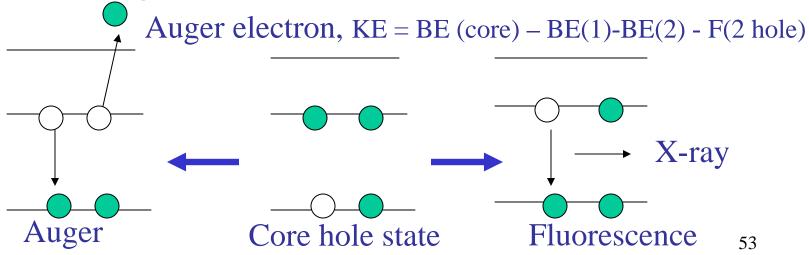
The attenuation length consideration is important in determining the thickness of the specimen in the XAFS measurements

#### What happens after absorption?

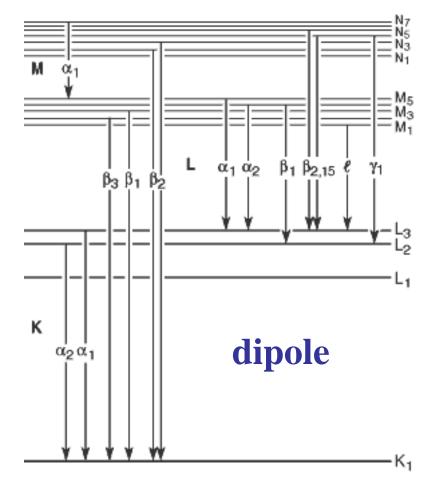
De-excitation of an atom with a core hole

Corehole decays via two primary processes:

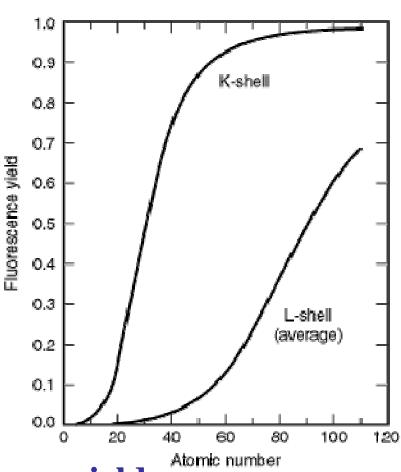
- Auger (electron channel, favorable route for shallow core levels, low z-elements)
- X-ray Fluorescence (photon channel, favorable route for deep core levels)
- Subsequent processes include cascade, defect formation, fragmentation of the molecule, luminescence



#### X-ray emission lines



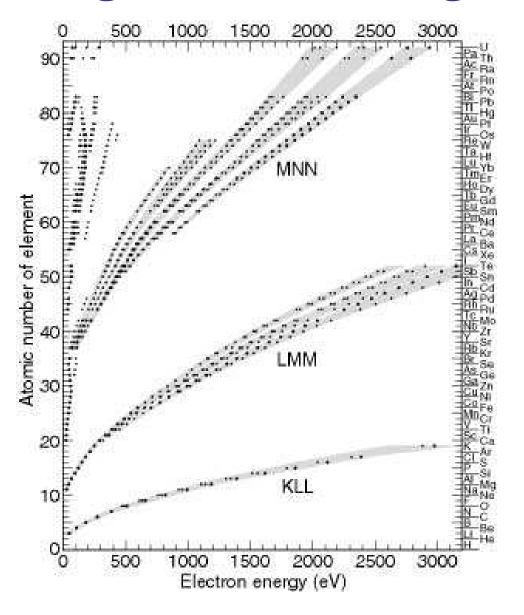
## Fluorescence yield for K & L shells\*



\*Auger yield = 1- fluorescence yield

## Auger electron energies

KLL means the Auger process involves one L shell electron fills the 1s hole, the other L shell electron is ejected



LMM means the Auger process involves one M shell electron fills the 2s/2phole, the other M shell electron is ejected